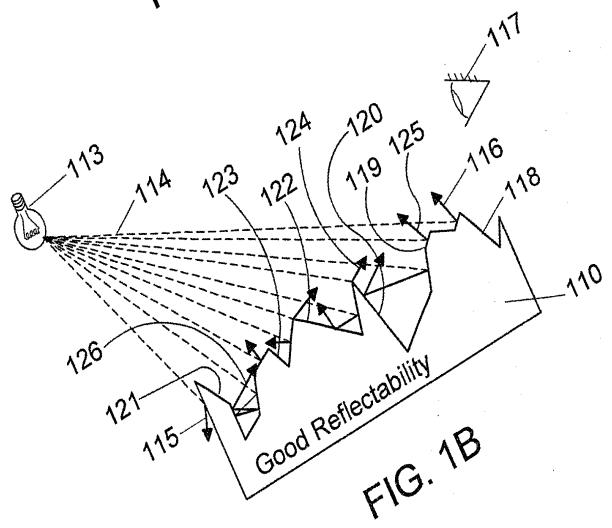


TOP EDGE - 3.38" (85.34 mm)



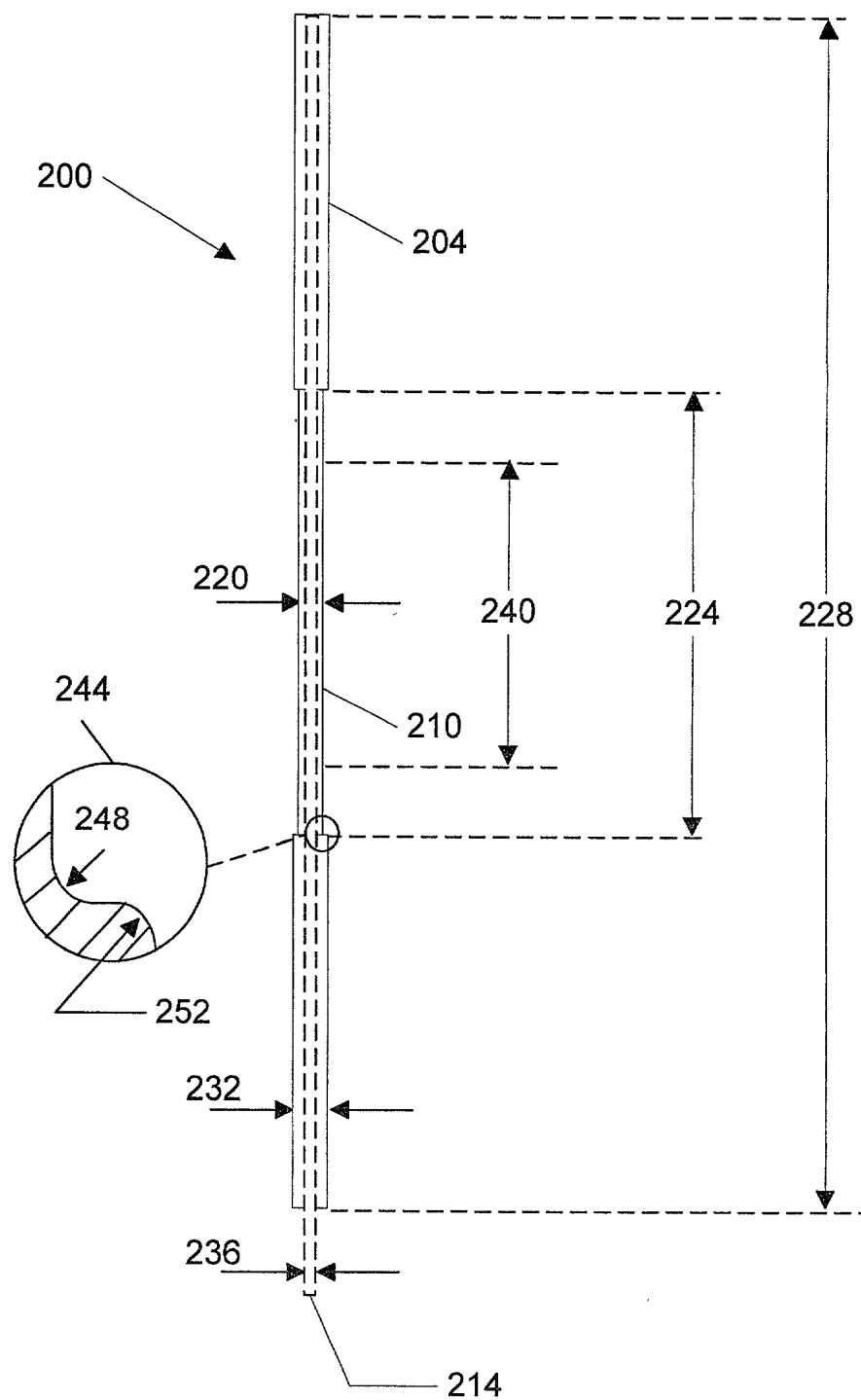


FIG. 2

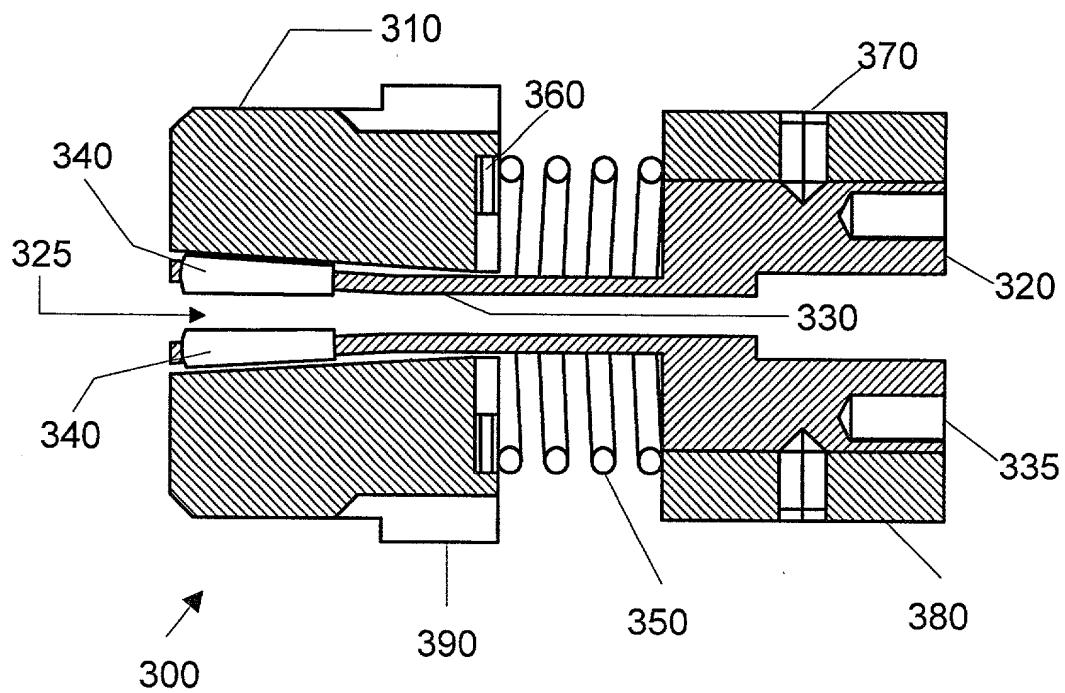


FIG. 3

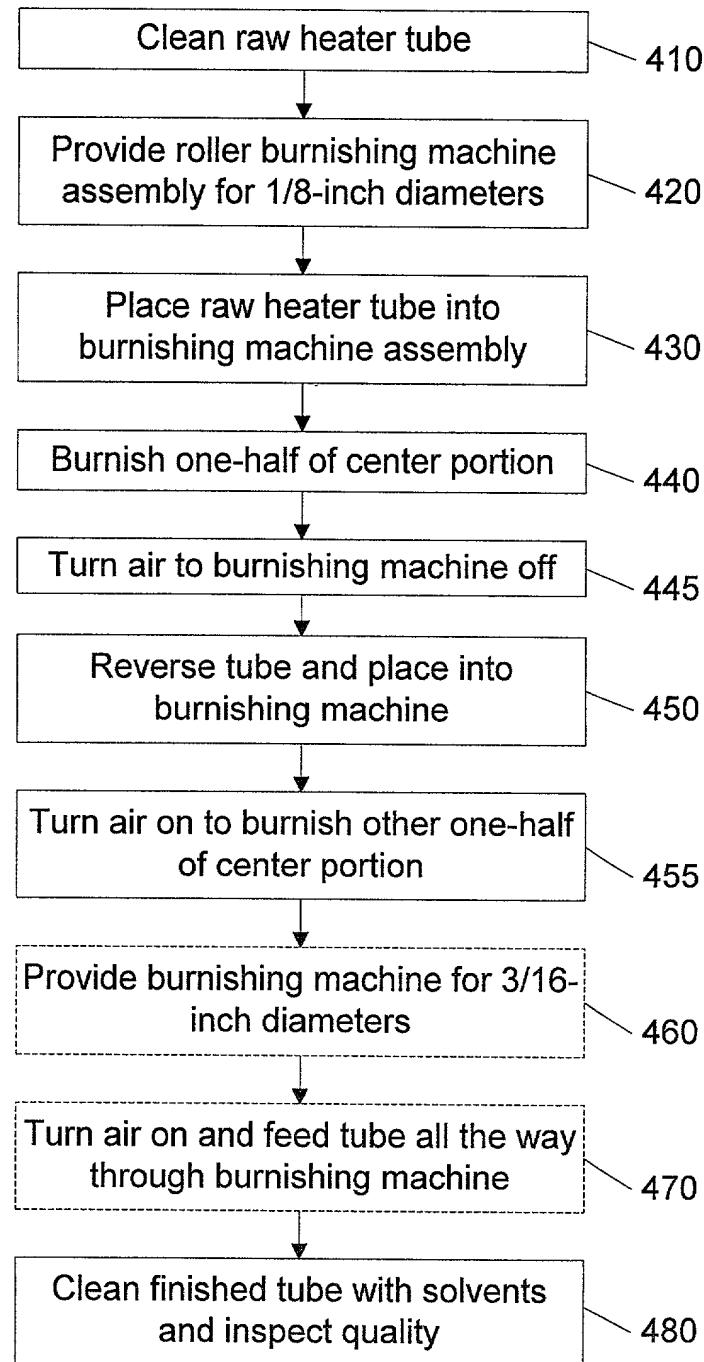


FIG. 4

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FIG. 5

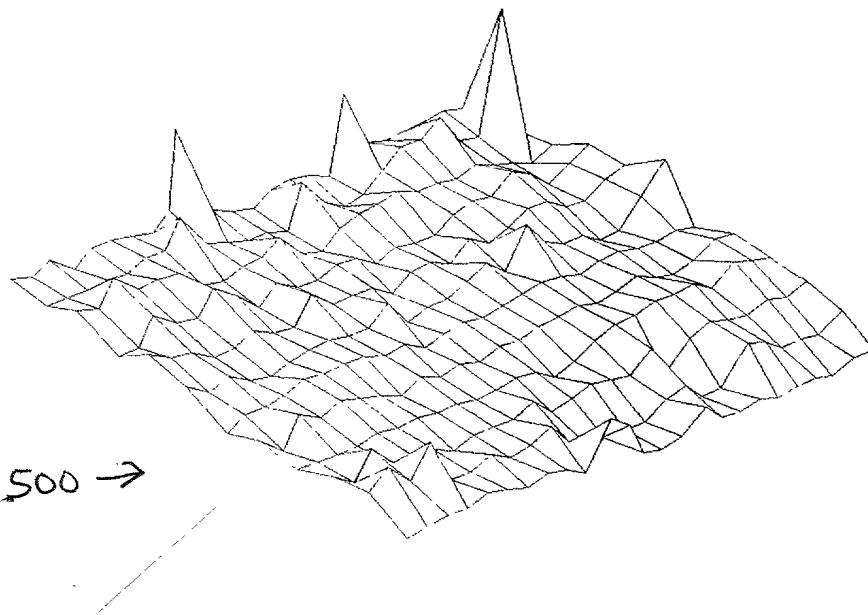
Mode : Spi  
Wavelength : 1510.0nm - G1  
Angle : 70.00°  
Thickness 1510.0nm  
n k  
Film 1 : 20.00nm 1.450 0.000  
Substrate : 2.650 -9.400

Wafer Size/Edge : 200x200 mm / 0.0 mm  
Start Coord X/Y : 1.000 / 1.000 mm  
End Coord X/Y : 111.000 / 12.000 mm  
Point Count X/Y : 25 / 12  
Measure Time : 14:08:20  
Measure Date : 01/09/99  
Wafer Id : BLANK  
filename : SD.RSM

Thick 1

Swivel Angle : 40°

Tilt Angle : 70°



	Mean	Sigma 1	Sigma 3	Range	Minimum	Maximum
Psi	34.0672°	0.5208°	1.5625°	2.5903°	33.1626°	35.7529°
Delta	161.9622°	0.5631°	1.6894°	4.5595°	158.4595°	163.0190°
Thick 1	-16.25nm	0.91nm	2.72nm	7.37nm	-17.96nm	-10.59nm